2SD2107

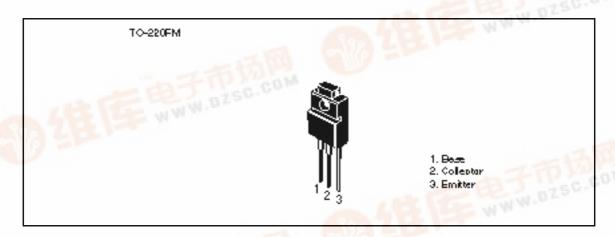
Silicon NPN Triple Diffused

HITACHI

Application

Low frequency power amplifier

Outline



Absolute Maximum Ratings $(Ta = 25^{\circ}C)$

Item	Symbol	Rating	Unit
Collector to base voltage	V_{CBO}	70	V
Collector to emitter voltage	V_{CEO}	60	V
Emitter to base voltage	V_{EBO}	5	V
Collector current	I _c	4	A ATSG.CO
Collector peak current	I _{C(peak)}	8	Α
Collector power dissipation	P _c	2	W
	P _c *1	25	
Junction temperature	CC COM TI	150	°C
Storage temperature	Tstg	-55 to +150	°C
N . 4 V I . T . 0500			

Note: 1. Value at $T_c = 25$ °C.



2SD2107

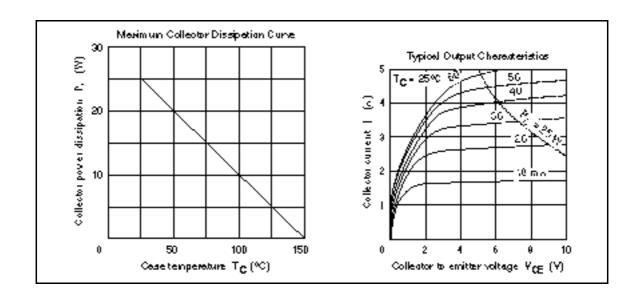
Electrical Characteristics ($Ta = 25^{\circ}C$)

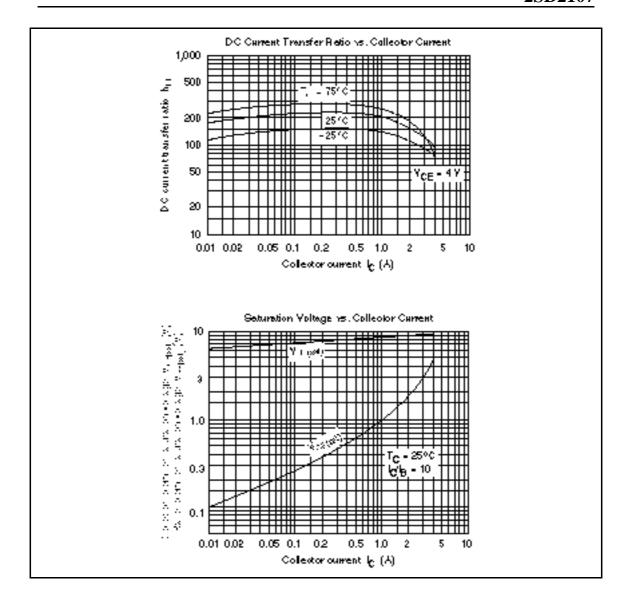
Item	Symbol	Min	Тур	Max	Unit	Test conditions
Collector to base breakdown voltage	$V_{(BR)CBO}$	70	_	_	V	$I_{c} = 10 \ \mu A, \ I_{e} = 0$
Collector to emitter breakdown voltage	$V_{\text{(BR)CEO}}$	60	_	_	V	I_{C} = 50 mA, R_{BE} =
Emitter to base breakdown voltage	$V_{(BR)EBO}$	5	_	_	V	$I_{E} = 10 \ \mu A, \ I_{C} = 0$
Collector cutoff current	I _{CBO}	_	_	10	μA	$V_{CB} = 60 \text{ V}, I_{E} = 0$
	I _{CEO}		_	10	_	V _{CE} = 50 V, R _{BE} =
DC current transfer ratio	h _{FE1} *2	60	_	200		$V_{CE} = 4 \text{ V}, I_{C} = 1 \text{ A}^{*1}$
	h _{FE2}	35	_			$V_{CE} = 4 \text{ V}, I_{C} = 0.1 \text{ A}^{*1}$
Base to emitter voltage	V_{BE}		_	1.0	V	$V_{CE} = 4 \text{ V}, I_{C} = 1 \text{ A}^{*1}$
Collector to emitter saturation voltage	$V_{\text{CE(sat)}}$	_	_	1.0	V	$I_{\rm C} = 2 \text{ A}, I_{\rm B} = 0.2 \text{ A}^{*1}$
Base to emitter saturation voltage	$V_{BE(sat)}$	_	_	1.2	V	$I_{\rm C} = 2 \text{ A}, I_{\rm B} = 0.2 \text{ A}^{*1}$

Notes: 1. Pulse test.

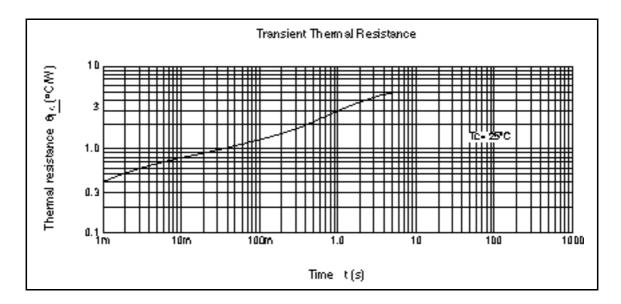
2. The 2SD2107 is grouped by $h_{\mbox{\tiny FE1}}$ as follows.

В	С
60 to 120	100 to 200





2SD2107



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Histochi, Ltd.
Semiconductor & IC Div.
Neppon Bidg, 2-6-2, Ohte-medii, Chiyode-ku, Tokyo 100, Jepan Tet Tokyo (03, 3270-2111
Fex: (03, 3270-5109)

For Aurther in formelion write to: Historii Americe, Utd. Semiconductor & IC Div. 2000 Sierra Foint Perlayay Briebene, CA. 94005-4835

USA Tet 415-589-8300 Fax 415-583-4207 Hitechi Burope GmbH Bedronic Componente Group Continental Burope Dornacher Straße 3 D-85622 Feldkirchen München Tet 089-9 94 80-0 Fex 089-9 20 30 00 Hitachi Burope Ltd.
Bedronic Componente Div.
Nothern Burope Headquertere
Whitebrook Perk
Lower Cook hem Road
Meidenhead
Berkehine SL68Y/Å
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Tet 0628-585000
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Hitachi Asia (Hong Kong) Ltd. Unit 705, North Towar, World Finance Cantra, Harbour City, Carton Road Taim Sha Taul, Kowloon Hong Kong Tat 27:592/18 Fax: 27:306074